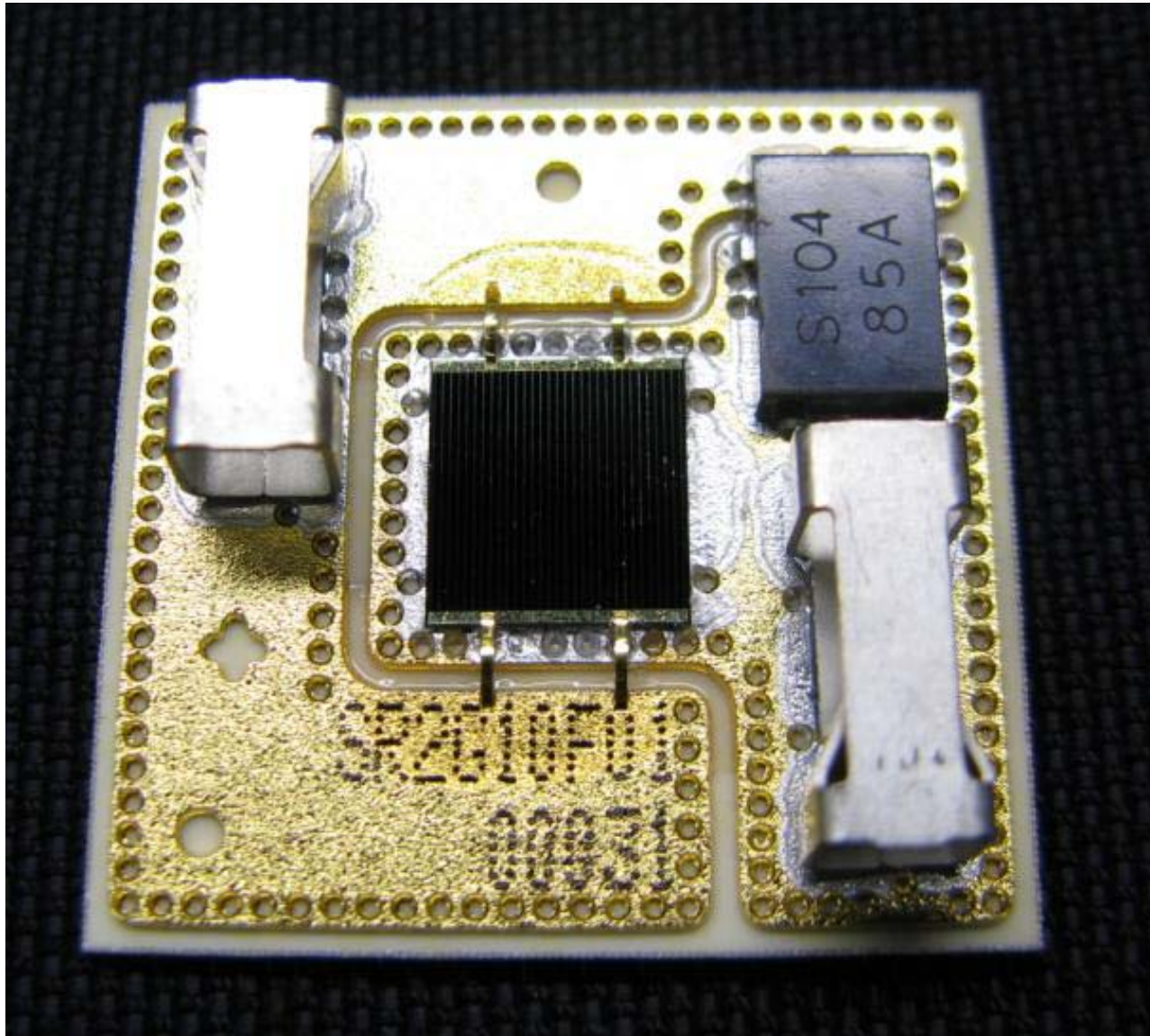


empower with light™

Reliability Testing Of High-Concentration PV Modules And Soiling Issues

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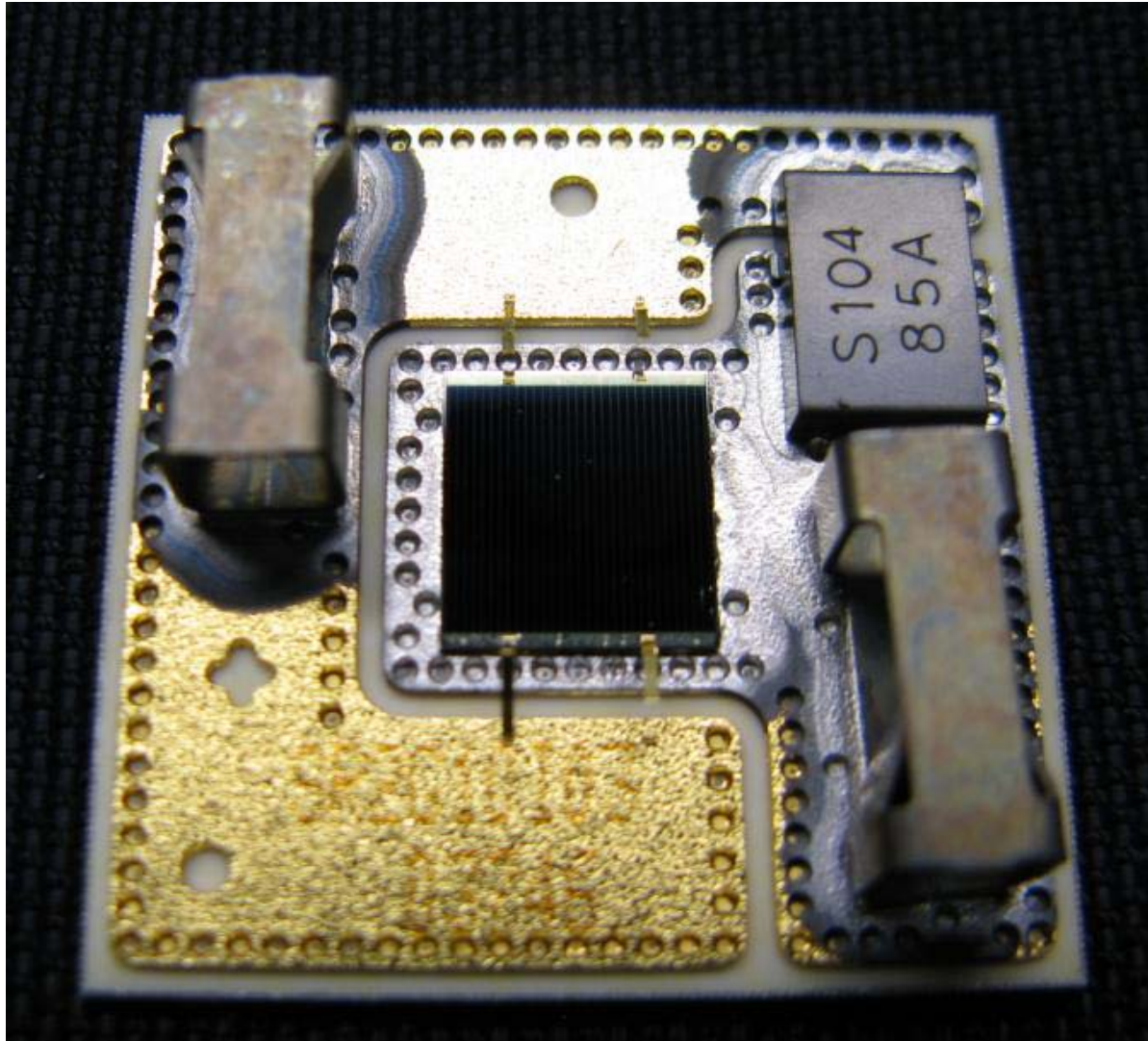
5.5 mm x 5.5 mm III-V cell on diffusion bonded copper substrate



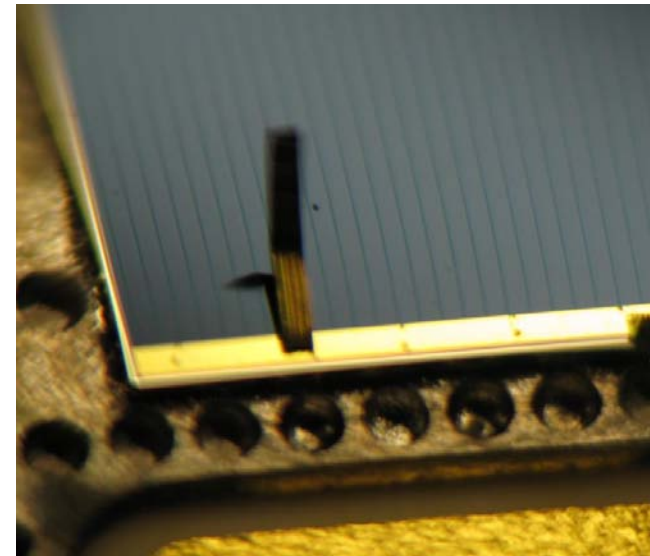
Qualification plan draws from IEC 62108 and various military standards

1	Thermal Aging for Intermetallics	300°C	Pass
2	Powered Thermal Cycling	-40 to 110°C	TBD
	Stud Pull		TBD
3	Humidity Freeze	-40 to 110°C pre-condition -40°C to 85°C test	Pass
	Stud Pull		TBD
4	Damp Heat	85°C	Pass
5	Mechanical Shock	30" drop	Pass
	Vibration	random vibration	Pass
	Liquid-Liquid Thermal Shock	-55 to 125°C	Pass
6	ESD Damage Threshold	8kV	TBD

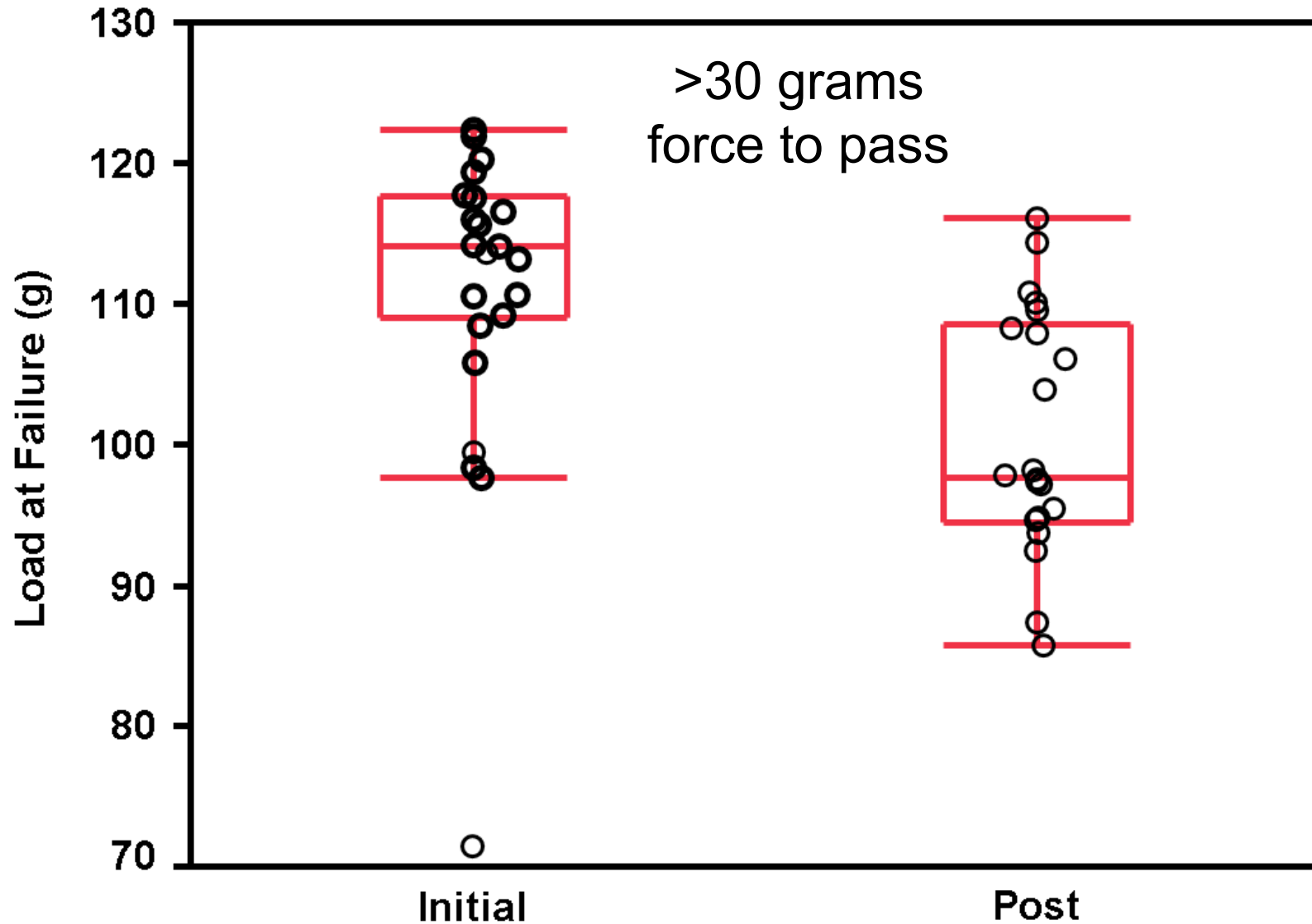
Thermal aging does not result in intermetallic phases and ribbons fail first



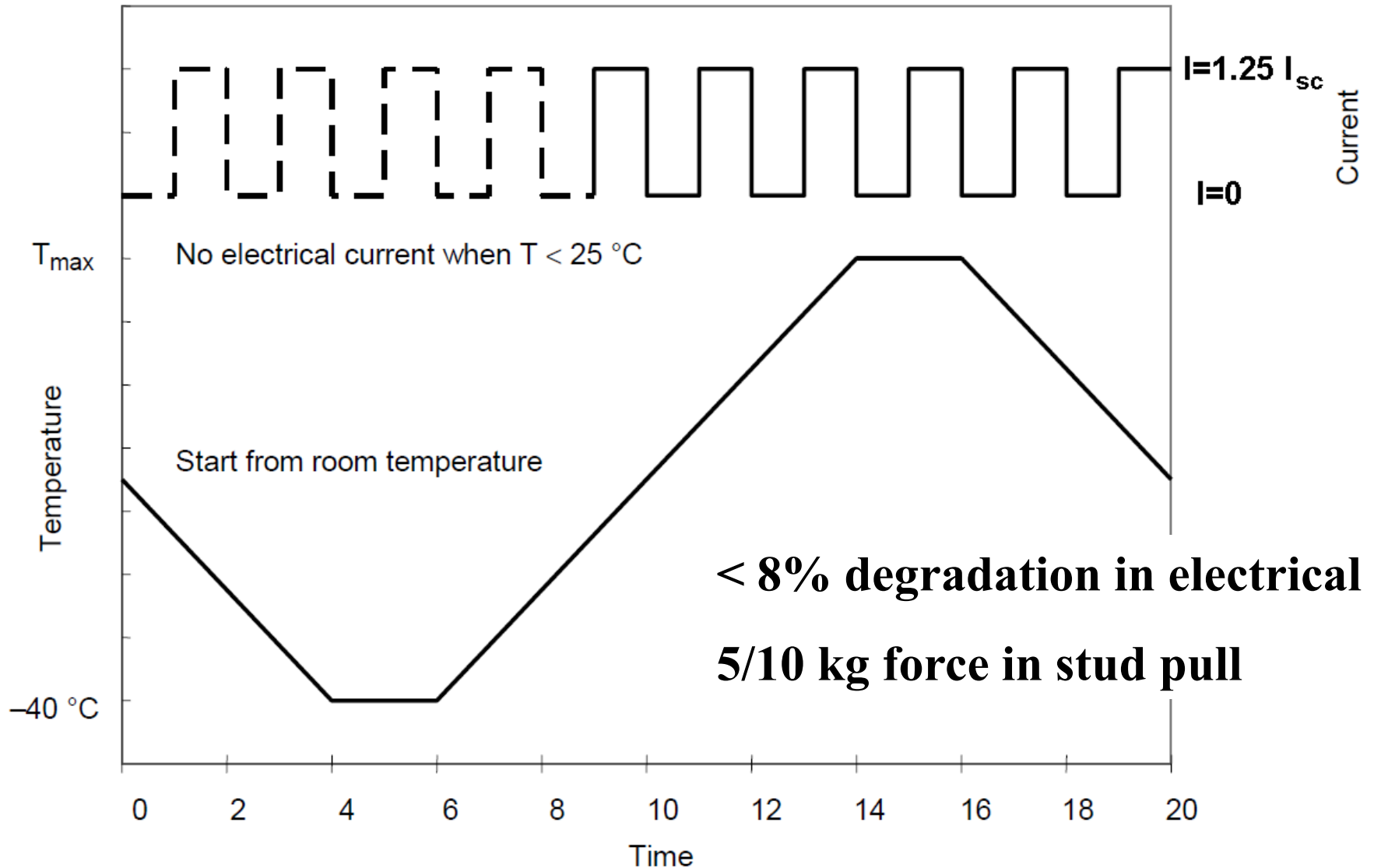
300°C for 1h



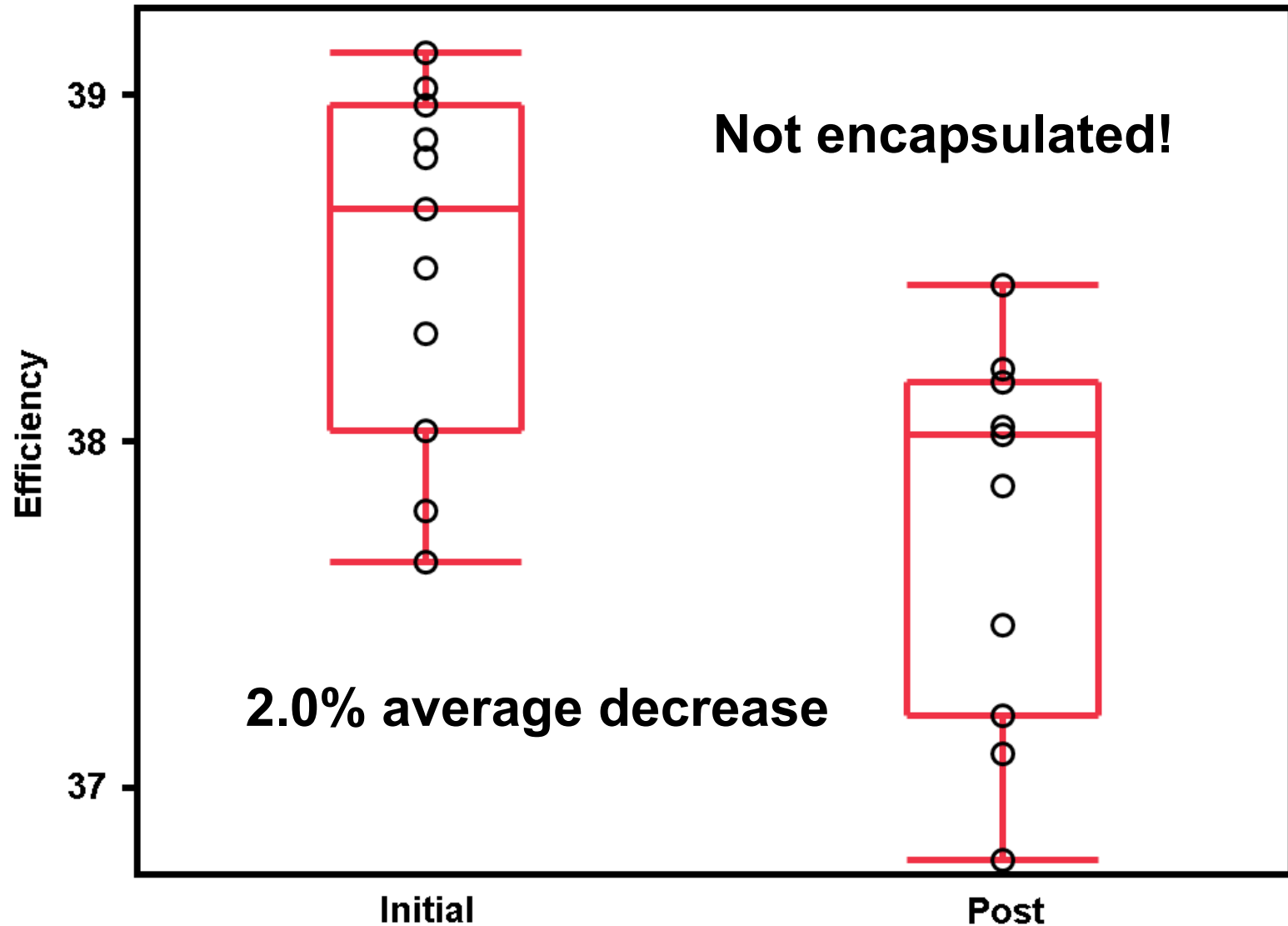
Thermal aging of ribbon bonds does not significantly reduce pull strength



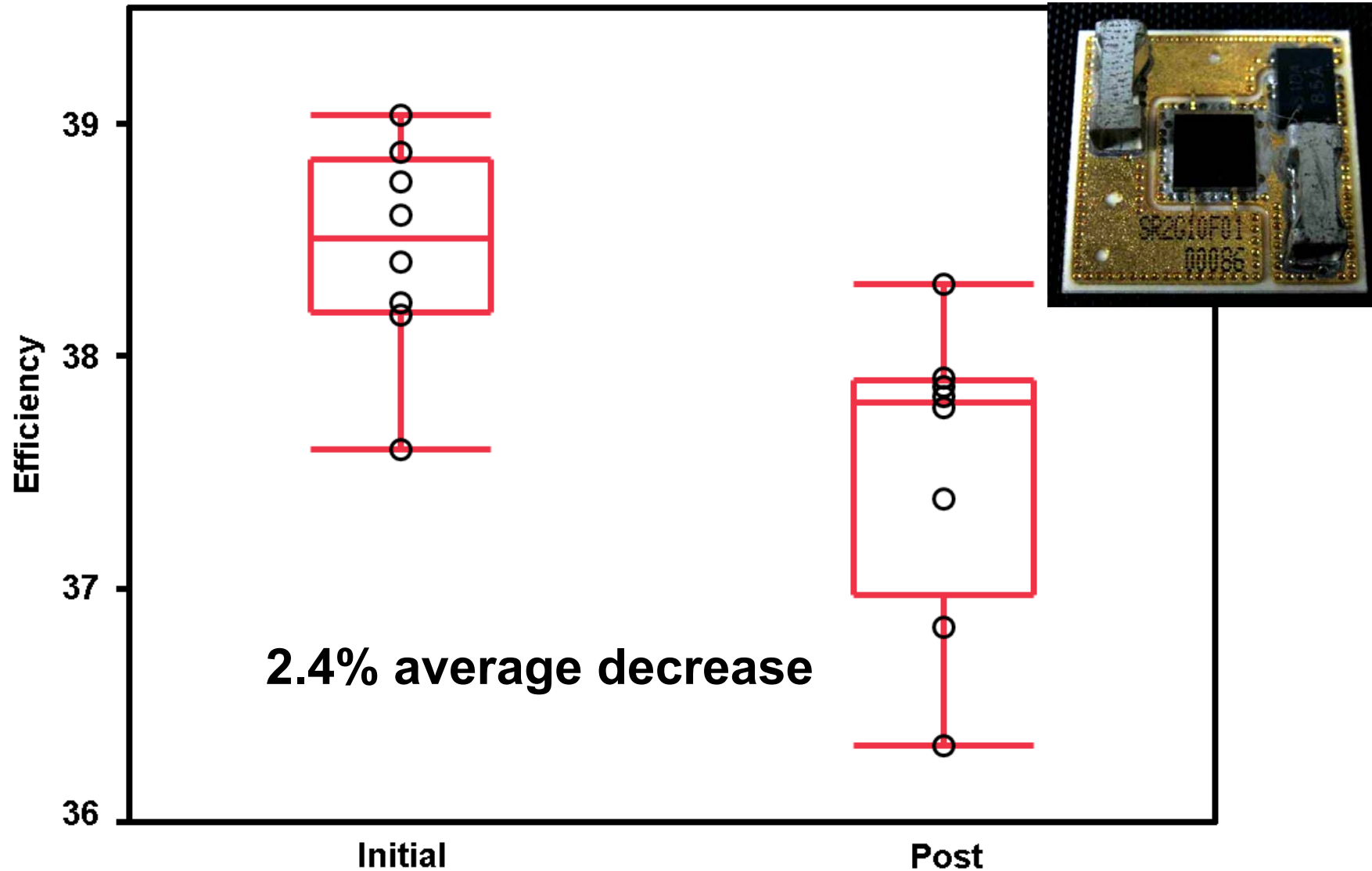
Powered thermal cycling for electrical properties and stud pull for solder adhesion



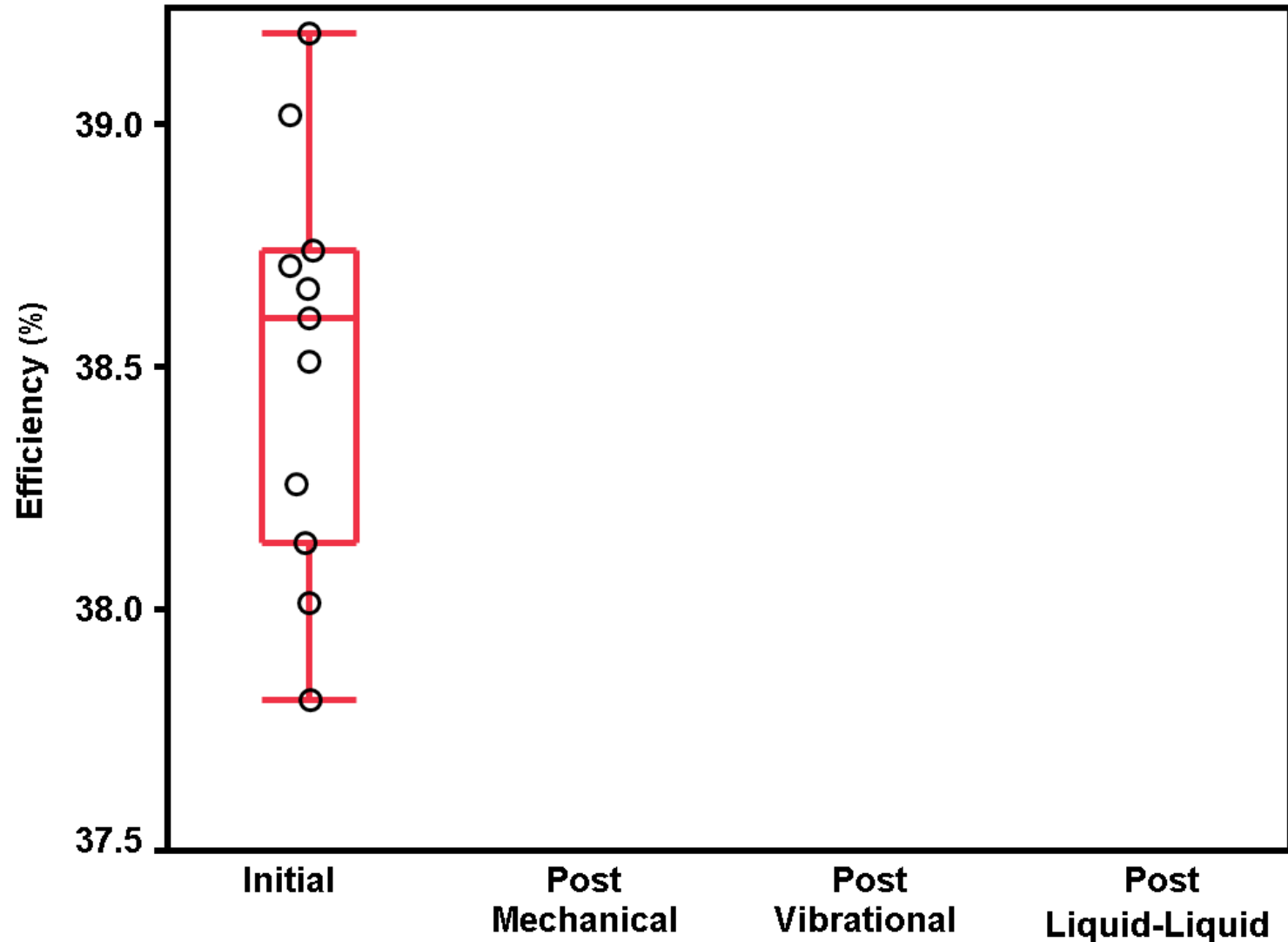
Damp freeze impacts efficiency, but the decrease is less than 8%



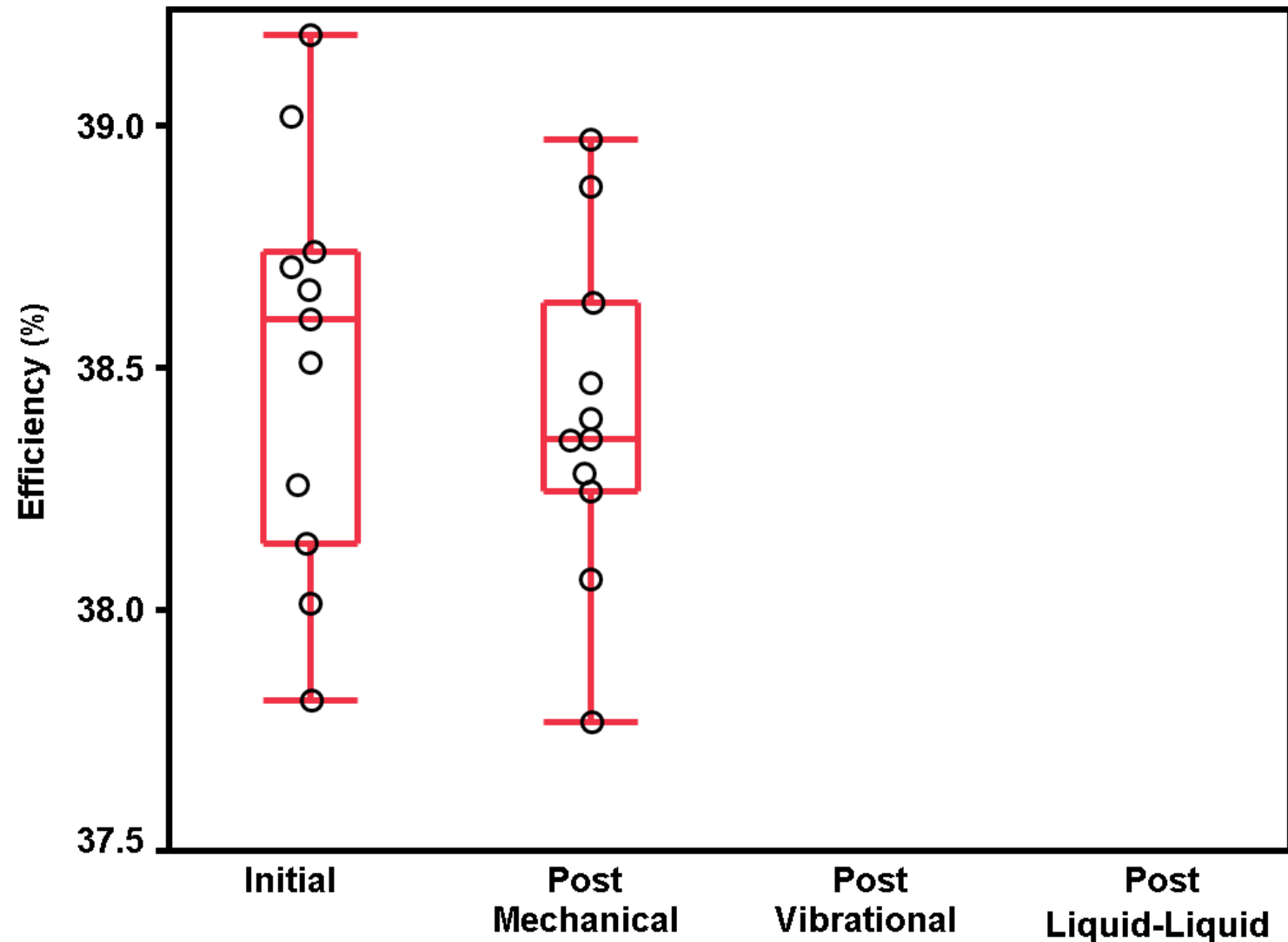
Damp heat impacts efficiency, but the decrease is less than 8%



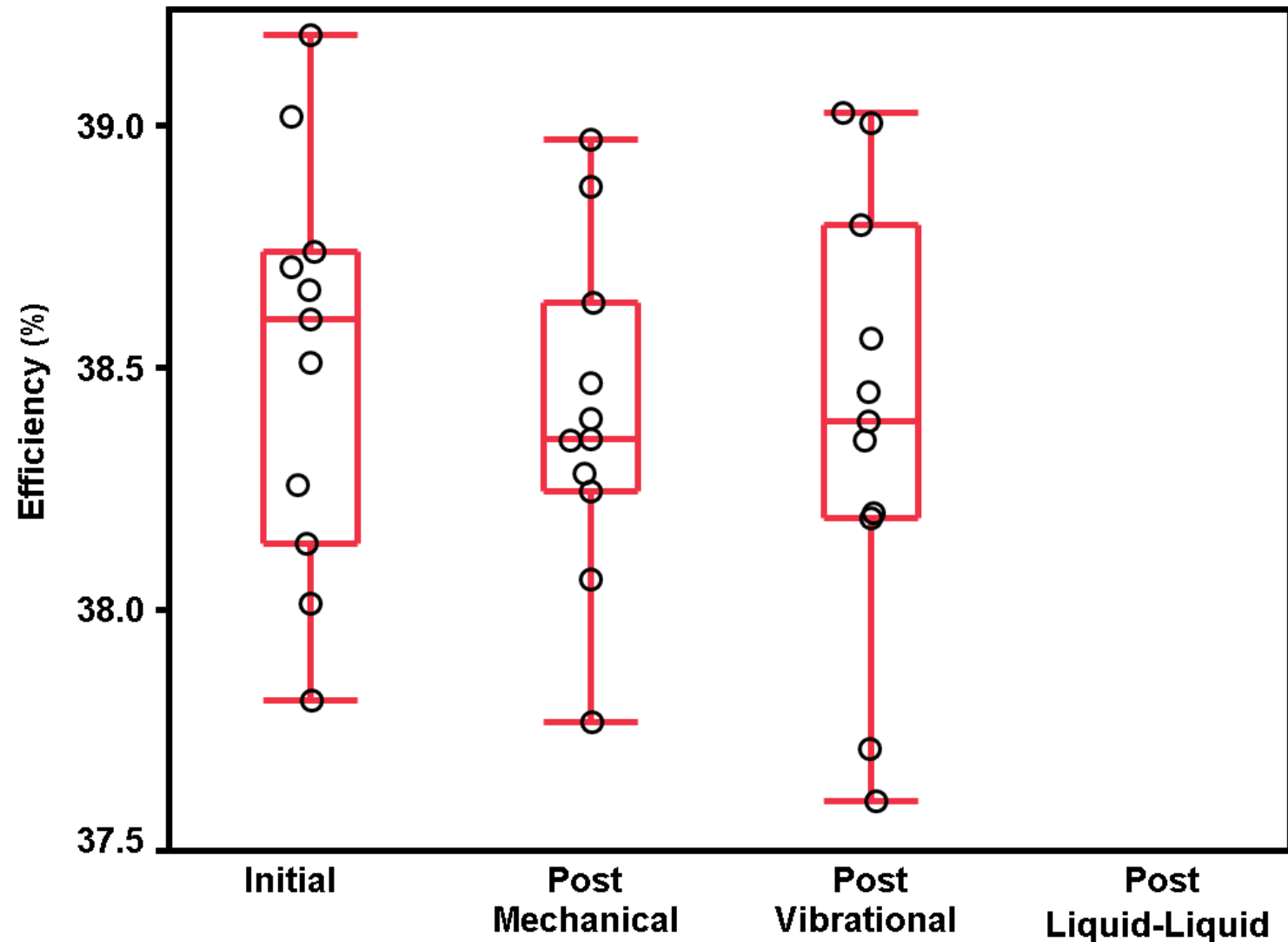
Initial efficiency whisker plot showing an average efficiency between 38% and 39%



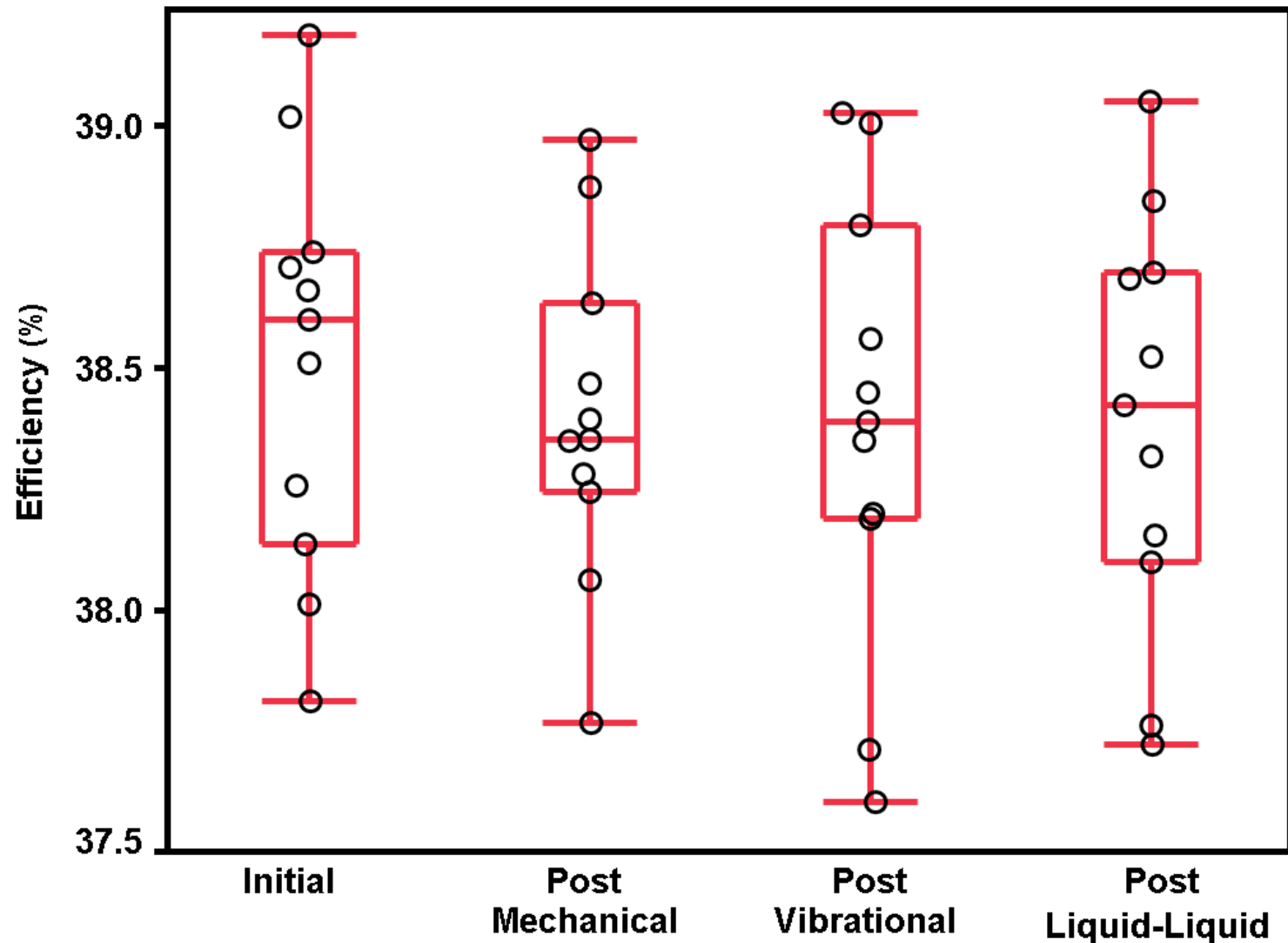
Efficiency whisker plot after mechanical stress showing no difference after the test



Efficiency whisker plot after vibrational stress showing no difference after the test



Efficiency whisker plot after liquid-liquid shock showing no difference after the test





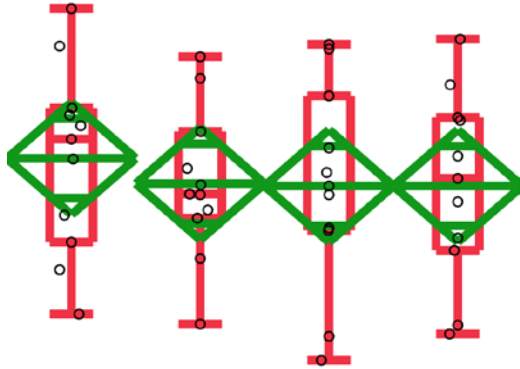
I-V measurements

ESD followed by I-V in increments

leakage current $< 8 \text{ mA}$ at 2.2 V

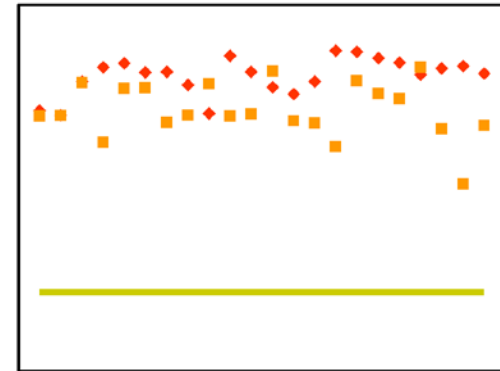
similar parts to 4kV have shown
 $< 1 \text{ mA}$ at 2.2 V

The 5.5 x 5.5 mm sub-assembly is a robust product against strife testing



**Thermal and mechanical shock
have no effect on efficiency**

**Thermal aging does not compromise
ribbon bond strength**



**Humidity with temperature impacts
performance, but within acceptable limits**

Air Force test location in Maui (leeward side)



Panels near the ground were untouched
elevated panels cleaned weekly

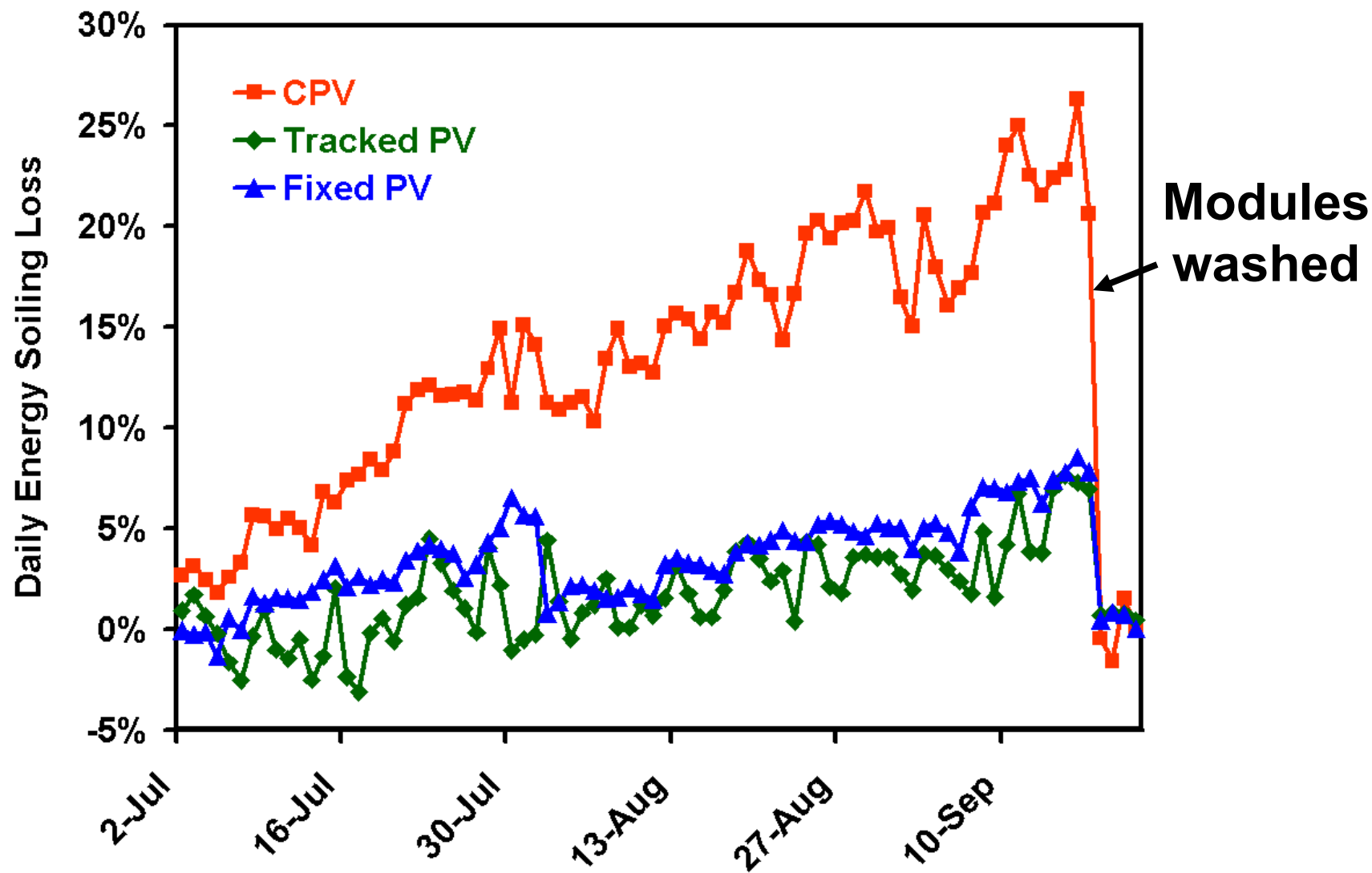


Soiling loss calculated using the following

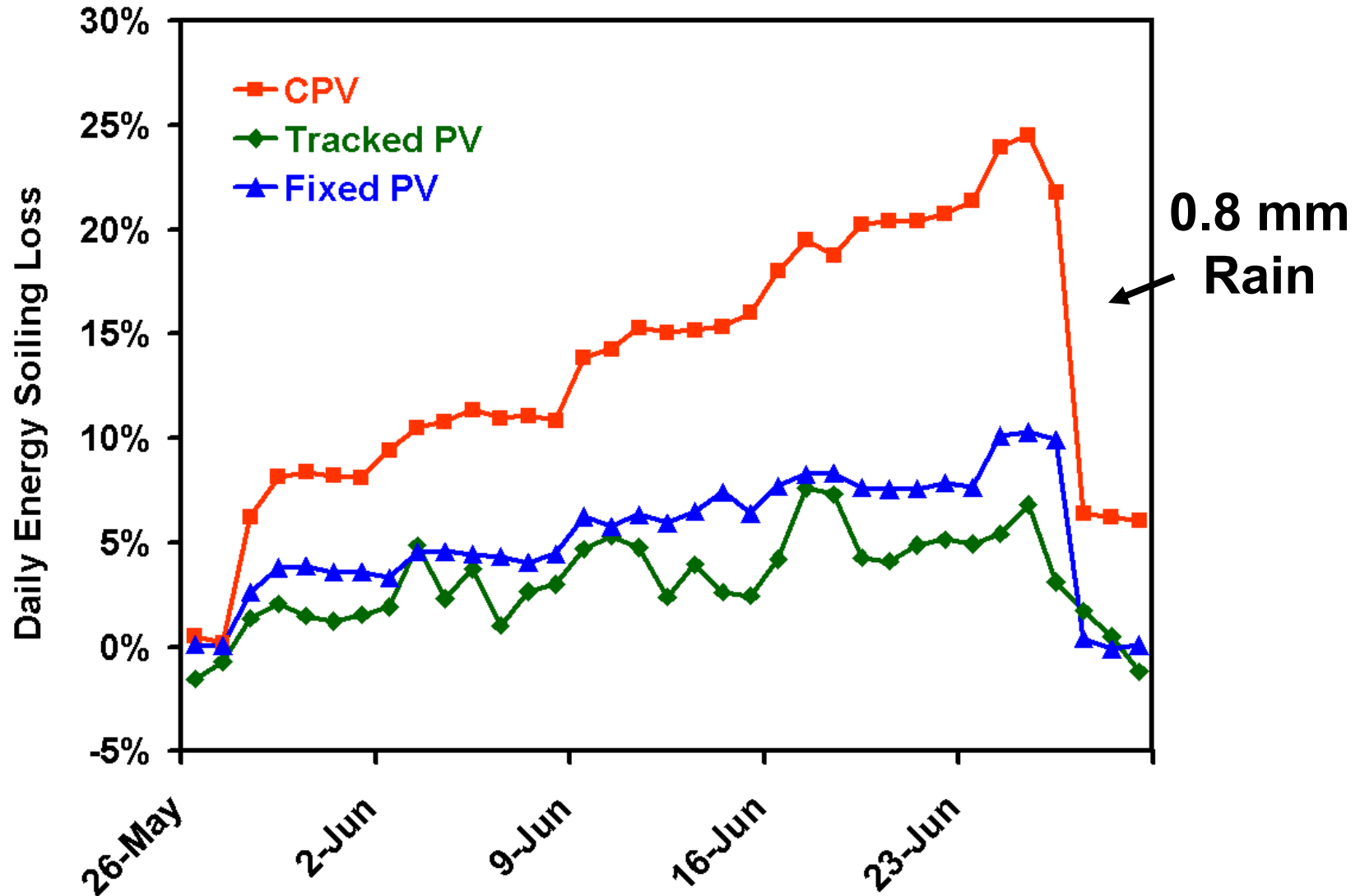
$$SL = \frac{E_{\text{clean}} - E_{\text{dirty}}}{E_{\text{clean}}}$$

Dirt accumulates at high rates in this environment

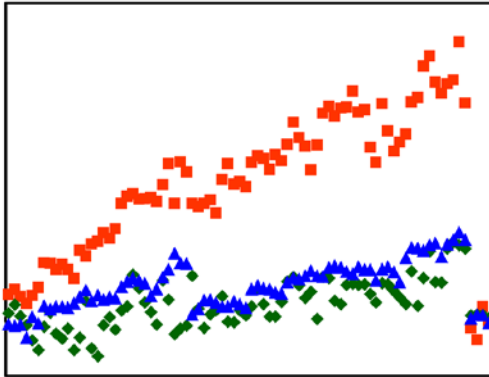
Dirt accumulation on CPV has a strong impact on electrical performance



Dirt accumulation may be easily removed by small (0.8 mm) rain events



Clean lenses are crucial for efficient CPV power generation



**The data show what we knew:
Dirt accumulation affects efficiency**

**Washing and rain events restore
performance to as-installed**



**Soiling effects and mitigation measures
will be site and season dependent**



